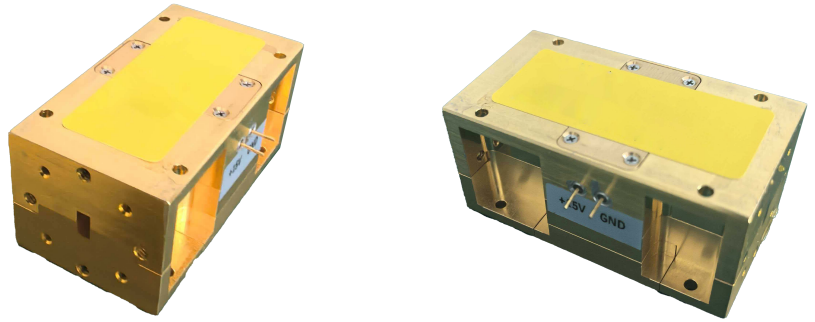


V-Band Power Amplifier Module, 40-70GHz

Performance characteristics

- Frequency Range: 40GHz~70GHz
- Power Gain: 20dB
- Psat(CW): 24.5dBm
- PAE: 10%
- +15V@0.2 A (Quiescent)
- Dimensions: 3.33mm×1.45mm×0.05mm



Product Description

GPAm-4070 is a power amplifier die implemented with GaN HEMT transistors and fabricated on a 0.13 μm GaN power MMIC process. It operates across the 40 GHz to 70 GHz frequency band with power gain higher than 20 dB, typical Psat of 24.5 dBm and typical power-added efficiency (PAE) of 10% under continuous-wave (CW) operation. The die features backside via grounding and dual supply operation, with typical bias conditions of $V_d = +15\text{ V}$ and $V_g = -2.2\text{ V}$.

DC Electrical Specifications ($T_A = +25^\circ\text{C}$)

Parameter	Symbol	Min	Typ	Max	Unit
Operating Gate Voltage	V_g	-	-2.2	-	V
Operating Drain Voltage	V_d	12	15	18	V
Quiescent Drain Current	I_d	-	200	-	mA
Dynamic Drain Current	I_{dd}	-	-	260	mA
Quiescent Gate Current	I_g	-	-	0.1	mA
Dynamic Gate Current	I_{gg}	-	-	1	mA

RF Electrical Specifications ($T_A = +25^\circ\text{C}$, $V_d = +15\text{V}$, $V_g = -2.2\text{V}$)

Parameter	Symbol	Min	Typ	Max	Unit
Frequency Range	f	40~70			GHz
Psat	Psat	24.5	-	27.5	dBm
Power Gain	G_p	20	-	23	dB
Power Gain Flatness	ΔG_p	-	-	± 1.5	dB
PAE	PAE	-	10	-	%
Linear Gain	Gain		30		dB
Linear Gain Flatness	ΔGain			± 5	dB
Input VSWR	VSWR(in)		3	5.5	-

Note:

- 1) All dies undergo 100% on-wafer DC test and 100% RF test.
- 2) Unless specified otherwise, all characteristic curves in this datasheet are measured under the following conditions:
 $V_d = +15\text{ V}$, $V_g = -2.2\text{ V}$, $P_{in} = 5\text{ dBm}$, CW operation.

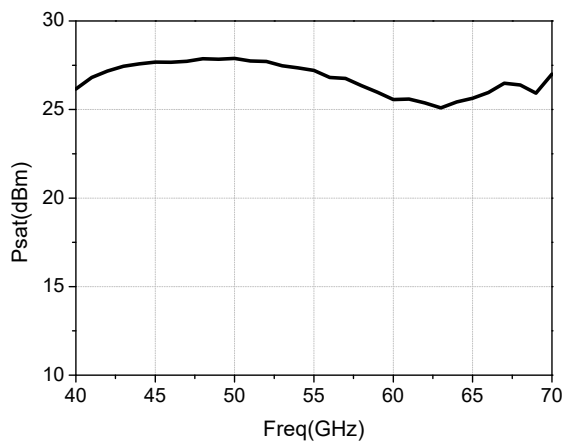
V-Band Power Amplifier Module, 40-70GHz

Absolute Maximum Ratings

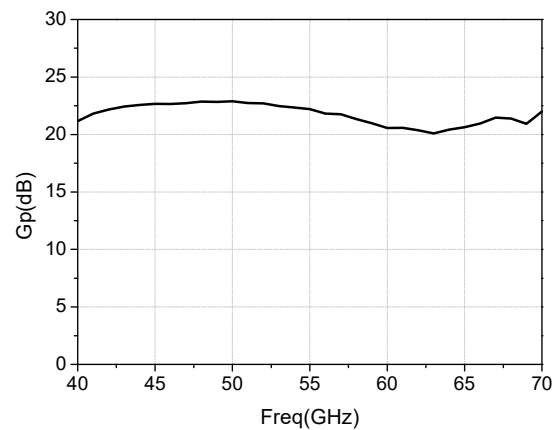
Parameter	Symbol	Value
Maximum Drain-Source Voltage	V _d	+20V
Minimum Gate-Source Voltage	V _g	-6V
Maximum CW Input RF Power (CW)	P _p	+12dBm
Storage Temperature	T _{STG}	-65°C ~ +150°C
Maximum Operating Channel Temperature	T _{op}	+200°C
Load Mismatch Tolerance (Destruction-Proof)	Z ₀	5: 1

Typical Curves (V_d=+15V, V_g=-2.2V)

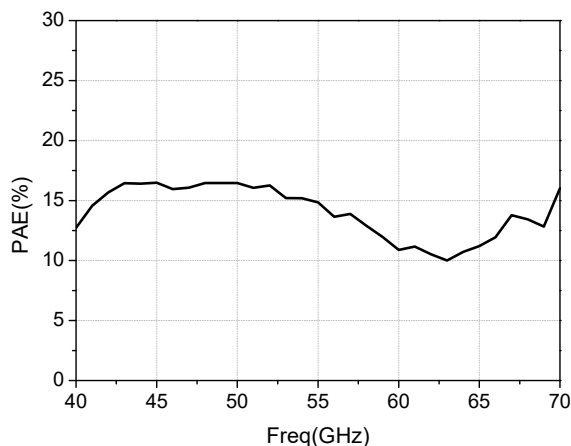
Psatvs. Frequency (P_{in}=5dBm)



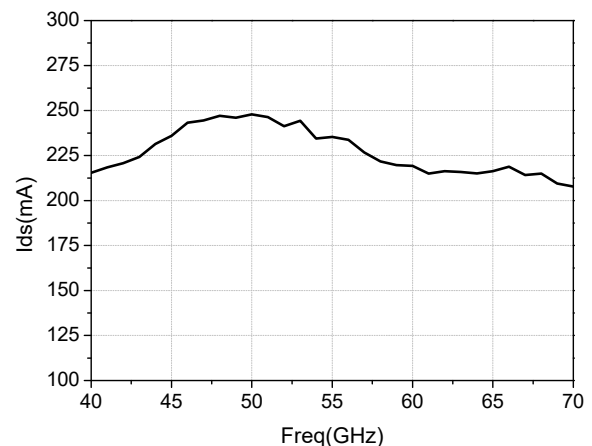
Powergainvs. Frequency (P_{in}=5dBm)



Efficiencyvs. Frequency (P_{in}=5dBm)

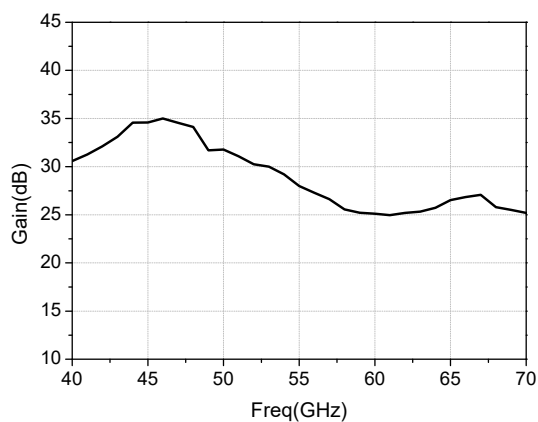


Dynamicdraincurrentvs. Frequency (P_{in}=5dBm)

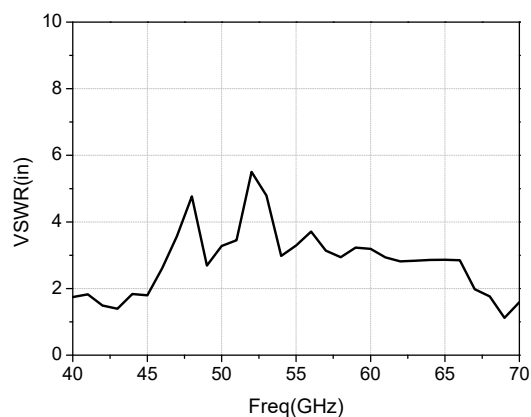


V-Band Power Amplifier Module, 40-70GHz

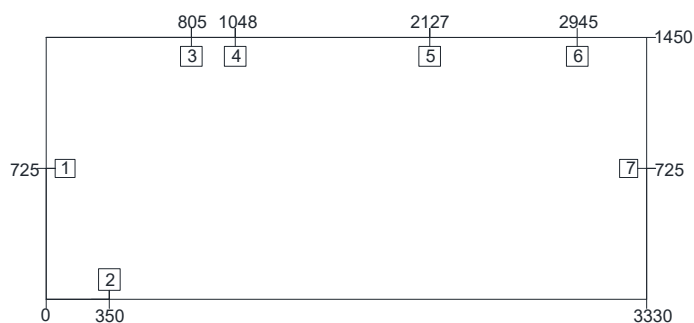
Smallsignalgainvs. Frequency ($P_{in}=-10\text{dBm}$)



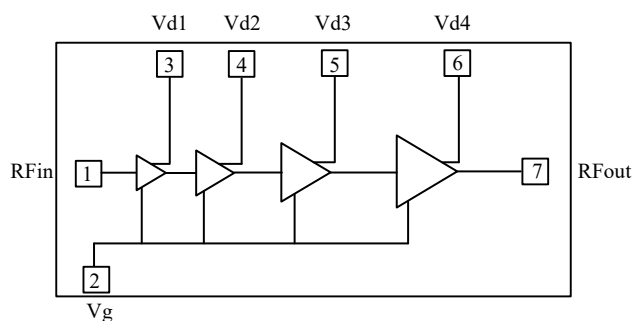
InputVSWRvs. Frequency ($P_{in}=-10\text{dBm}$)



Outline Dimensions & Bond Pad Layout Drawing



Block Diagram



Notes:

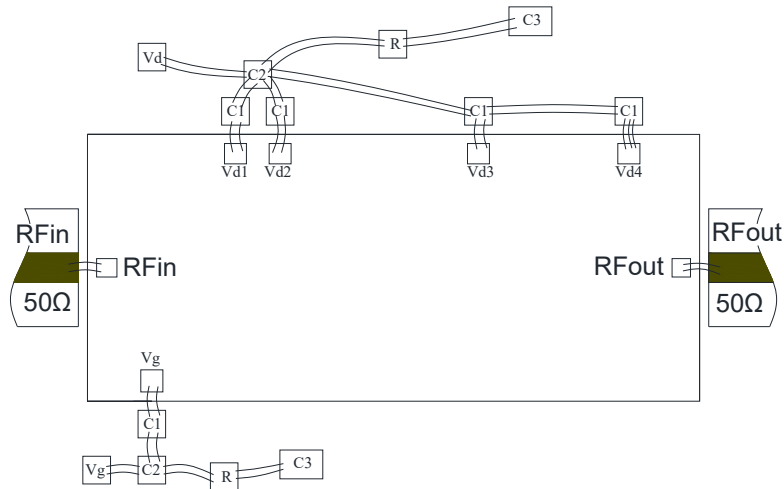
All dimensional units shown in the drawing are μm ;
tolerance for outline dimensions is $\pm 50 \mu\text{m}$.

Bond Pad Layout

No.	Symbol	Function	Dimension
1	RFin	RF Input Bond Pad	$110 \times 100 \mu\text{m}^2$
2	Vg	Gate Bond Pad	$120 \times 120 \mu\text{m}^2$
3	Vd1	Drain Bond Pad	$120 \times 110 \mu\text{m}^2$
4	Vd2	Drain Bond Pad	$120 \times 110 \mu\text{m}^2$
5	Vd3	Drain Bond Pad	$120 \times 110 \mu\text{m}^2$
6	Vd4	Drain Bond Pad	$120 \times 110 \mu\text{m}^2$
7	RFout	RF Output Bond Pad	$100 \times 100 \mu\text{m}^2$

V-Band Power Amplifier Module, 40-70GHz

Recommended Assembly Schematic



Notes:

- 1) External component values: C1=100 pF, C2=1000 pF, C3=10000 pF. Resistor R is a 10 Ω die resistor, model NC6101C-E is recommended. All capacitors shall be placed as close to the die as possible, with a maximum distance not exceeding 300 μ m.
- 2) The length of gold bonding wires for RF input and output shall be controlled within 300 μ m $\pm$ 50 μ m, kept as short as feasible.

Precautions

- 1) All MMIC dies shall be stored in a dry, clean nitrogen atmosphere.
- 2) The die substrate is made of brittle 6H-SiC. Handle with extreme care to prevent mechanical damage.
- 3) A passivation protection layer covers the die surface. Assembly must be performed in a clean environment to avoid excessive surface contamination.
- 4) The thermal expansion coefficient of the carrier material shall be close to that of 6H-SiC substrate (linear thermal expansion coefficient of 6H-SiC: $4.2 \times 10^{-6} / ^\circ\text{C}$). Recommended carrier materials include CuMoCu, CuMo, CuW or other materials with superior heat dissipation performance.
- 5) Voids between the die and carrier substrate shall be eliminated during mounting. Ensure sufficient heat dissipation from the housing or carrier.
- 6) AuSn solder eutectic sintering is recommended. Sintering temperature shall not exceed 300°C with total sintering time $\leq$ 30 seconds. Avoid rapid temperature fluctuations; apply gradual temperature ramp-up and ramp-down profiles.
- 7) Gold bonding wires with diameter 25 μ m ~ 30 μ m are recommended. The chuck temperature of the wire bonder shall not exceed 250°C; minimize bonding duration and avoid abrupt temperature changes during bonding.
- 8) Power-up sequence: Apply gate bias first, then drain bias. Power-down sequence: Remove drain bias first, then gate bias.
- 9) Strict ESD protection must be implemented during all handling and assembly steps. Wear grounded ESD wrist straps, and ensure proper grounding for sintering and wire bonding equipment.
- 10) Contact your supplier for technical support if any problems occur.



This device is sensitive to electrostatic discharge. Strict ESD precautions are required during handling.